Ministry of Supply - D.L.R.D./S.R.D.E.

VALVE ELECTRONIC CV4094

Specification MOS/CV4094 Issue 1 Dated 8.1.59	SECU	RITY
To be read in conjunction with K.1001, BS448 and BS1409	Specification Unclassified	<u>Valve</u> Unclassified

----- Indicates a change

				-			
Type of Valve - Reliable R.F. Beam Tetrod Cut Off Cathode - Directly Heated Envelope - Glass Metallised Prototype - VX9186	MARKING See K1001/4 except that the valve shall only be marked with the CV No. factory and date code						
RATING (All limiting values are absolute) Filament Voltage (V) Filament Current (mA)	1.25	NOTE	Sec App. 1 4 BS 448/B5G/I				
Max. Anode Voltage (V) Max. Screen Voltage (V) Max. Cathode Current (mA) Max. Bulb Temperature (°C)	100 100 7.0		CONNECTIONS				
Max. Shock (Short Duration) (g) Max. Acceleration (Continuous	100 450 5		PIN		(mad dot		
Operation) (g)	,		1 a (red dot) 2 82 3 f(-), bp ₁ , M 4 81 5 f(+), bp ₂				
Typical Operating Conditions Measured at Va = Vg ₂ = 45V · Vg ₁ = 0 Rg ₁ = 2 MΩ Anode Current (mA) Screen Current	3.0 0.9		See BS448/BS Size Referen See App. 1 1	ce No	· 1		
Mutual Conductance (mA/V)	2.0		Dimension (millimetr	-	Min.	Max.	
Capacitances (pF) Cin (nom.) Cout (nom.) Ca, g ₁ (max.)	4.0 4.0 0.01		A. Overall Length Diameter B. Minor C. Major Lead Length		- - 38.1 POSITION	38•15 7•264 9•804	
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To be performed in addition to those applicable in K.1001. Tests shall be performed in the specified order unless otherwise agreed with the inspecting Authority.

V	nditions - unl f(V) Va(•25 45			Rg ₁ (Me	gohms)		de met met un dem gener	
K. 1001		0 1 0 2 2 4 4		Insp.	Sym-	Lin	Units	
Ref.	Test	Test Conditions	%	Level	bol	Min.	Max.	Onius
7•1	Glass Strain	No Voltages	6.5	I				
	GROUP A Electrode Insulation Reverse Grid Current Contact Potential GROUP B Filament Current Anode Current	Vf = 0 Vg ₁ - all = -100V Vg ₂ - all = -100V Va - all = -100V Rg ₁ = 500 kΩ max. Va = Vg ₂ = 55V Vg ₁ = -1.0V Vf = 1.25V Va = Vg ₂ = 0 Rg ₁ = 200 kΩ Combined AQL	1.0 0.65	100% 100% 100%	R R R Ig ₁ Ig ₁	100 100 100 - 0.25	0•5 122 4•1	MΩ MΩ MΩ μΑ μΑ μΑ
	Screen Grid Current Mutual Conductance (1)		0.65	11	Ig ₂	1•5	1•3 2•5	mA/V
	GROUP C Mutual Conductance (2)	Combined AQL Vf = 1.0V	6.5 2.5	I	gm	1•2	2•5	mA/V
	Mutual Conductance (3) Nuclear Conductance (4) Anode Resistance	Vf = 1.0V Take reading after 15 mins. √C z o·9√	2.5 2.5 2.5	I	gm. S≁∖ Rea.	1•2 (-1 0•2	2•5	mA/V mAIV MΩ
	R.F. Noise	E _{sig} = 30 mVrms Ref. K.1006 (4.10.3.1)	2•5	I				

K.1001	Test	Test conditions	AQL	Insp.	Sym-	Lim	its	Units
Ref.			Я	Level	bol	Min.	Max.	
5•12	GROUP D Lead Fragility		6.5	IA				
	Filament Anode Short	Note 1		T.A.				
	Capacitances	Measured on a 1Mc/s bridge with the valve mounted in a fully screened socket. No shield.	6•5	IC	Ca, g ₁ Cin Cout	3	0•01 5 5	pF pF pF
	Functional Test			T.A.		opera	y in W	shall isfac- .S. A40
	GROUP E							
11•3	Fatigue	Acceleration = 5g peak min. Time = 99 hours Note 2		IA				
	Post Fatigue	Combined AQL	4.0					
	Tests R.F. Noise	As in Group C	2•5					
	Mutual Conductance (1)		2•5		gm	1•2		mA/V
11.4	Shock	No voltages. Hammer Angle 30°		IA				
	Post Shock Tests	Combined AQL	4.0					
	R.F. Noise	As in Group C	2.5					
	Mutual Conductance (1)		2•5		gm	1•2		mA/V
	GROUP F							
A VI/5	Life	Rs ₁ = 5 MΩ						
A VI/ 5•1	Stability Life Test							
	Mutual Conductance (2)	Vf = 1.0V	1.0	I	gm	1•2		mA/V
			-	-		-	CTT	094/1/3

CV 4094/1/3

TESTS (Cont'd)

K•1001	Test	est Test Conditions	AQL	Insp.	Sym-	Lim	Units	
Ref.	1680	rest Conditions	76	Level	bol	Min.	Max.	onius
A VI/ 5•3	GROUP F (Cont'd) Intermittent Life Test Life Test End Point	Combined AQL	6•5	IA				
A VI/ 5.6	(500 hrs.) Inoperatives		2•5					
	Mutual Conductance (1)		2•5		gm	1•2		mA/V
	Electrode Insulation	Vf = 0 Vg ₁ - all = -100V Vg ₂ - all = -100V Va - all = -100V	4.0		R R R	50 50 50		MΩ MΩ 1
	Life Test End Point (1,000hrs.)	Combined AQL	10	IA				
A VI/ 5.6	Inoperatives		4.0					,
	Mutual Conductance (1)		4.0		gm	1•2		mA/V
	Reverse Grid Current	As in Group A	4.0		Ig ₁	-	1.0	μА
	Contact Potential	$Vf = 1.25V$ $Va = Vg_2 = 0$ $Rg_1 = 200k\Omega$	4.0		Ig ₁	To be		
	Electrode Insulation	Vf = 0 Vg ₄ - all = -100V Vg ₂ - all = -100V Va - all = -100V	6.5		R R R	30 30 30		Μ Ο Μ Ο Μ Ο
	GROUP G							
A IX/ 2.4 and 2.5	Electrical retest after 28 days hold- ing period			100%				
A VI/	Inoperatives		0.5					
5.6	Mutual Conductance (1)				gm	1•5	2•5	mA/V
	Reverse Grid Current	As in Group A	0.5		Ig ₁	-	0.5	μА

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NOTES

- 1. Raise Vf until filament opens. Test for filament to anode short only. After performance of the filament burn out test, if the short circuit shall pass in excess of five times the rated filament current without burning out the short circuit, the valve shall be deemed a failure. This test shall be performed by a Service Laboratory on three valves which shall be in addition to the required number for Type Approval samples. Manufacturers' data are not required for this test.
- Filament voltage and H.T. voltage switched simultaneously 1 min. on and 3 min. off throughout duration of test. Frequency = 170 cps. The valves to be vibrated in each of three mutually perpendicular planes in turn for periods of 30, 30 and 39 hours. One plane to include the longitudinal axis of the valve.

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AMENDMENT No. 1

Page 2 GROUP C

Immediately	following	the	test	for	"Mutual	Conductance	(3)"

Conductance (4) Vf = 0.8V 2.5 I

Add new test as follows: -

2100	220 002.0							
		Test	<u>A</u> QL	Insp.	Sym-	Limi	<u>ts</u>	
<u>T</u> e	st	Conditions	%	Level		Min.	Max.	Units
Mutual	•							

gm 1.1

April, 1959. T.V.C. for S.R.D.E. N.54788/D.

ELECTRONIC VALVE SPECIFICATIONS

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AMENDMENT NO.2 On Page 4, under GROUP F

(Cont'd) Intermittent Life Test

(2) Immediately following the above, in column headed "Test"

TVC for SRDE

August, 1959

MAS

N.71076/D

ELECTRONIC VALVE SPECIFICATION

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AMENDMENT NO. 3

Page 1 Base

Delete:- See Appendix 1 to CV.2237

Dimensions

Delete: - See Appendix 1 to CV.2237

21.3-62

Signals Radio Development Establishment

JANUARY, 1962. (8533)